



# **DCR1080G22**

## **Phase Control Thyristor**

		DS5227-1.3	August 2007	(LN25531)
FEATURES	V <sub>DRM</sub> I <sub>T(AV)</sub>	2200V 1083A		
Double Side Cooling	I <sub>⊤sм</sub> dV/dt*	14400A 1500V/µs		
High Surge Capability	dl/dt	500A/μs		

**High Power Drives** 

Static Switches

**VOLTAGE RATINGS** 

Part and Ordering

Number

DCR1080G22

DCR1080G20

DCR1080G18

High Voltage Power Supplies

**Repetitive Peak** 

Voltages  $V_{\text{DRM}}$  and  $V_{\text{RRM}}$ 

v

2200

2000

1800

Conditions

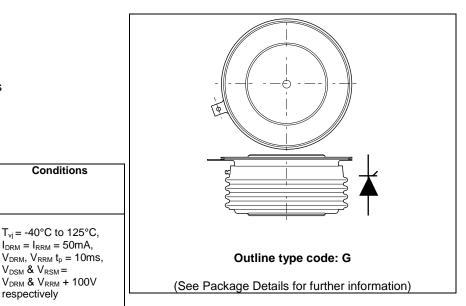
V<sub>DSM</sub> & V<sub>RSM</sub> =

respectively

**APPLICATIONS** 

•

#### \* Higher dV/dt selections available



Lower voltage grades available.

### **ORDERING INFORMATION**

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

#### DCR1080G22

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

Fig. 1 Package outline

### **KEY PARAMETERS**

 $T_{case} = 60^{\circ}C$  unless stated otherwise

Symbol	Parameter	Test Conditions		Units
Double Sid	de Cooled			
I <sub>T(AV)</sub>	Mean on-state current	Half wave resistive load	1083	А
I <sub>T(RMS)</sub>	RMS value	-	1701	А
Ι <sub>Τ</sub>	Continuous (direct) on-state current	-	1570	А

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### SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I <sub>TSM</sub>	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125^{\circ}C$	14.4	kA
l <sup>2</sup> t	I <sup>2</sup> t for fusing	$V_R = 0$	1.04	MA <sup>2</sup> s

### THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance – junction to case	Double side cooled	DC	-	0.0268	°C/W
		Single side cooled	Anode DC	-	0.0527	°C/W
			Cathode DC	-	0.0652	°C/W
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink	Clamping force 11.5kN	Double side	-	0.0072	°C/W
		(with mounting compound)	Single side	-	.0144	°C/W
$T_{vj}$	Virtual junction temperature	Blocking V <sub>DRM</sub> / <sub>VRRM</sub>		-	125	°C
T <sub>stg</sub>	Storage temperature range			-55	125	°C
F <sub>m</sub>	Clamping force			10	13	kN

### **DYNAMIC CHARACTERISTICS**

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I <sub>RRM</sub> /I <sub>DRM</sub>	Peak reverse and off-state current	At V <sub>RRM</sub> /V <sub>DRM</sub> , T <sub>case</sub> = 125°C		-	50	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V <sub>DRM</sub> , T <sub>j</sub> = 125°C, gate open		-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% $V_{\text{DRM}}$ to 2x $I_{\text{T(AV)}}$	Repetitive 50Hz	-	250	A/µs
		Gate source 30V, 10Ω, t <sub>r</sub> < 0.5μs, T <sub>j</sub> = 125°C	Non-repetitive	-	500	A/µs
V <sub>T(TO)</sub>	Threshold voltage – Low level	100A to 400A at T <sub>case</sub> = 125°C		-	0.75	V
	Threshold voltage – High level	400A to 3000A at T <sub>case</sub> = 125°C		-	0.95	V
r <sub>T</sub>	On-state slope resistance – Low level	100A to 400A at $T_{case} = 125^{\circ}C$		-	0.6513	mΩ
	On-state slope resistance – High level	400A to 3000A at T <sub>case</sub> = 125°C		-	0.3890	mΩ
t <sub>gd</sub>	Delay time	$V_D$ = 67% $V_{DRM}$ , gate source 30V, 10 $\Omega$ t <sub>r</sub> = 0.5µs, T <sub>j</sub> = 25°C		TBD	TBD	μs
t <sub>q</sub>	Turn-off time	$T_{j} = 125^{\circ}C, V_{R} = 200V, dI/dt = 5A/\mu s,$ $dV_{DR}/dt = 20V/\mu s \text{ linear}$		100	220	μs
Qs	Stored charge	$I_T = 2000A, T_j = 125^{\circ}C, dI/dt = 5A/\mu s,$		600	1100	μC
١L	Latching current	$T_j = 25^{\circ}C, V_D = 5V$		-	3	А
Ι <sub>Η</sub>	Holding current	$T_j = 25^{\circ}C, R_{G-K} = \infty, I_{TM} = 500A, I_T = 5A$		-	300	mA

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Symbol	Parameter	Test Conditions	Max.	Units
V <sub>GT</sub>	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25^{\circ}C$	1.5	V
$V_{GD}$	Gate non-trigger voltage	At 50% V <sub>DRM</sub> , T <sub>case</sub> = 125°C	0.4	V
I <sub>GT</sub>	Gate trigger current	$V_{DRM} = 5V, T_{case} = 25^{\circ}C$	250	mA
I <sub>GD</sub>	Gate non-trigger current	At 50% V <sub>DRM</sub> , T <sub>case</sub> = 125°C	10	mA

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### CURVES

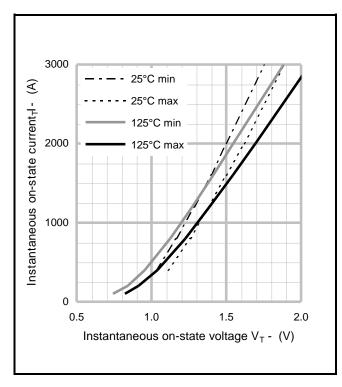


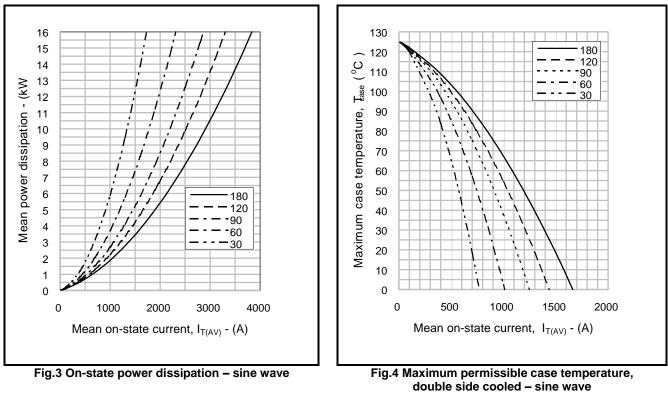
Fig.2 Maximum & minimum on-state characteristics

### **V<sub>TM</sub> EQUATION**

$$V_{TM} = A + BIn (I_T) + C.I_T + D.\sqrt{I_T}$$

Where A = 0.457916 B = 0.063349 C = 0.000289 D = 0.004142 these values are valid for  $T_j$  = 125°C for  $I_T$  50A to 3000A

### DCR1080G22



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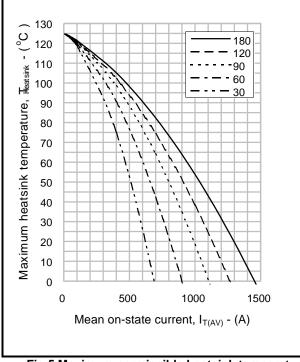


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

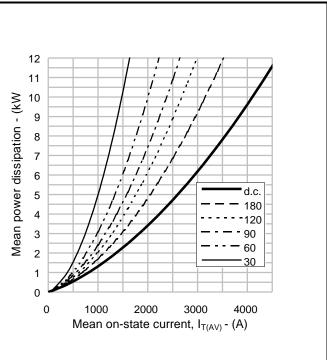
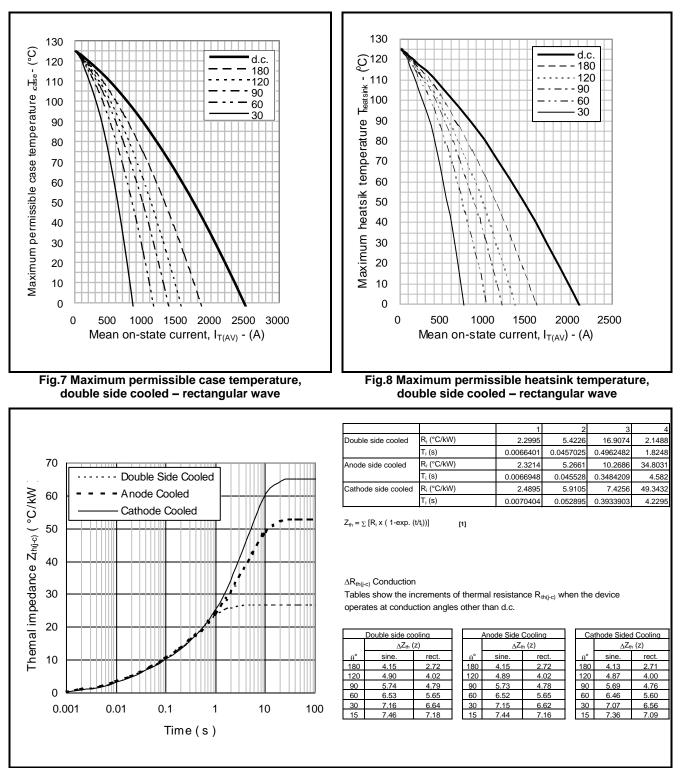
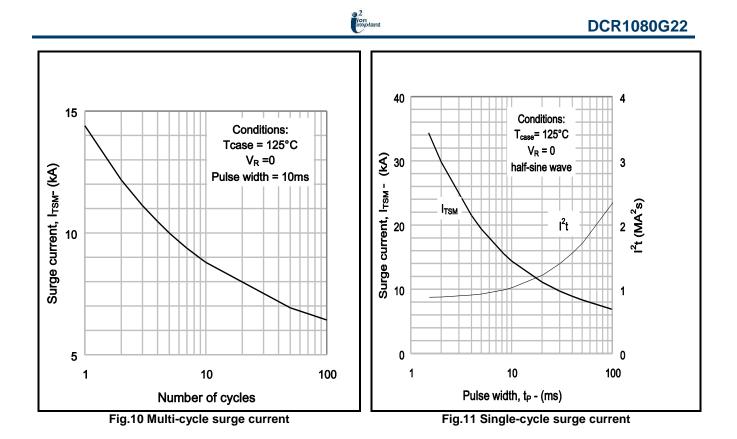
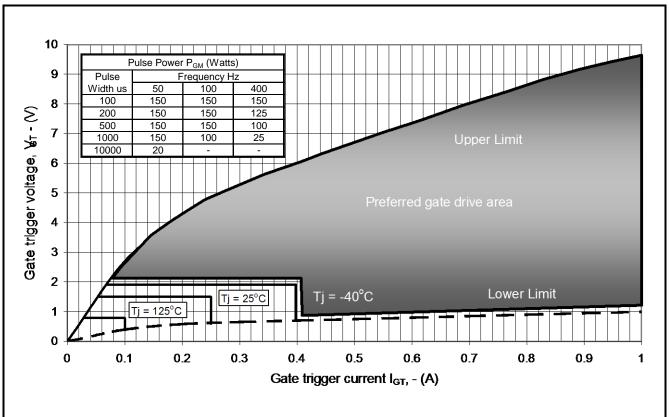


Fig.6 On-state power dissipation - rectangular wave









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Fig12 Gate Characteristics

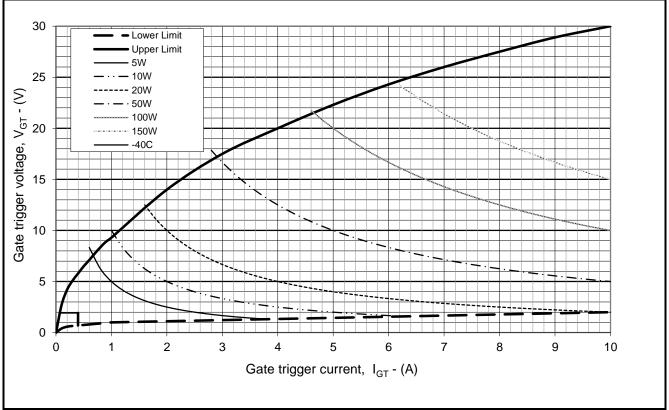


Fig. 13 Gate characteristics

### PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

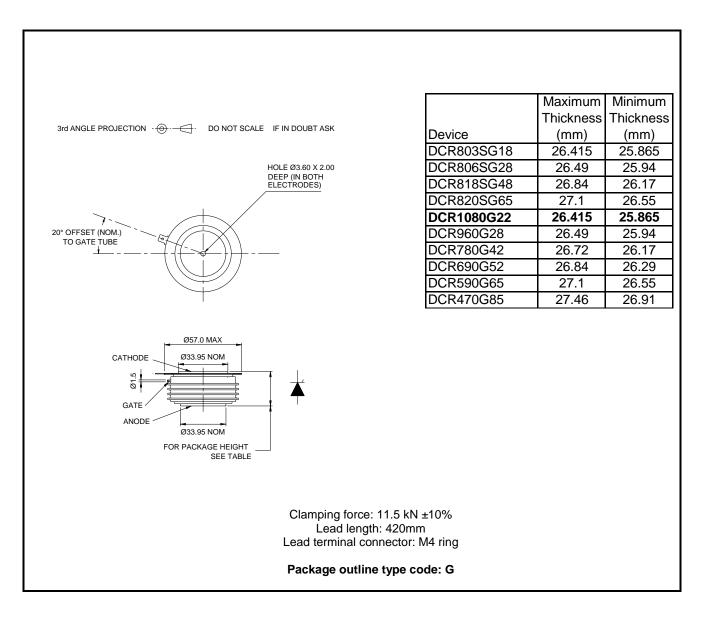


Fig.14 Package outline

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

#### HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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